

Notice of References Cited

Application/Control No.

10/608,187

Applicant(s)/Patent Under
Reexamination
BAEK ET AL.

Examiner

Jeff Piziali

Art Unit

2629

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,465,168 A	11-1995	Koden et al.	349/33
*	B	US-5,936,689 A	08-1999	Saishu et al.	349/123
*	C	US-5,949,391 A	09-1999	Saishu et al.	345/50
*	D	US-6,195,137 B1	02-2001	Inaba et al.	349/37
*	E	US-6,335,717 B1	01-2002	Hasegawa et al.	345/97
*	F	US-2002/0084973 A1	07-2002	Choi et al.	345/102
*	G	US-2004/0085280 A1	05-2004	Kim, Hong Chul	345/097
*	H	US-6,809,717 B2	10-2004	Asao et al.	345/102
*	I	US-6,853,436 B2	02-2005	Kim, Hong Chul	349/191
*	J	US-7,292,220 B2	11-2007	Choi et al.	345/102
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.